

DOCUMENT CHANGE REQUEST

161 DCR number Changes required for: General Originator: S Jeffery Date: 2005/03/08 Organisation: ESA/ESTEC Date sent: 2005/03/08 Status: IMPLEMENTED Title: CMOS Strobed Hex Inverter/Buffer, based on type 4502B Number: 9401/006 Issue: Other documents affected: Page: Figure 4(b)- Quiescent Current Test Table, page 35. Paragraph: Figure 4(b)- Quiescent Current Test Table, page 35. Original wording: Proposed wording: Change Pin Number 12 for Pattern Number 7 from 1 to 0. NB: as part of the conversion of this specification to ESCC format, this Figure will be incorporated into a note as shown in the attachment. Justification: To correct error in the specification. Attachments: Attachment_to_DCR_for_9401006.pdf, null Modifications: N/A Approval signature: Il Kiele Date signed: 2005-03-08

- 3. Quiescent Current shall be tested using the following input conditions:
 - (a)
 - All Inputs = $V_{|L}$ Inputs OD = INH = $V_{|L}$; all other inputs = $V_{|H}$ (b)
 - (c) (d)

 - (e)
 - Input INH = V_{IL} ; all other inputs = V_{IL} . Input INH = V_{IH} ; all other inputs = V_{IL} . Input OD = V_{IL} ; all other inputs = V_{IL} . Input OD = V_{IH} ; all other inputs = V_{IL} . Inputs OD = INH = V_{IH} ; all other inputs = V_{IL} . Input INH = V_{IL} ; all other inputs = V_{IH} . All inputs = V_{IH} . (f)
 - (g)
 - (h)